



Test Report issued under the responsibility of:



TEST REPORT
IEC 60269-4
Low-voltage fuses
Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices

Report Number..... : 03601-A-16CB0076-S-B

Date of issue : 2016-09-12

Total number of pages : 30

Applicant's name : Zhejiang Tengen Electrics Co., Ltd.

Address : Tengen Industry Zone, Liushi Town, Yueqing City, Zhejiang Province.

Test specification:

Standard : IEC 60269-4 (Fifth Edition) + A1:2012
see also IEC 60269-1:2006 (Fourth edition) + A1:2009

Test procedure : CB Scheme

Non-standard test method.....: N/A

Test Report Form No. : IEC60269_4B

Test Report Form(s) Originator.... : CQC

Master TRF : Dated 2012-12

Copyright © 2012 Worldwide System for Conformity Testing and Certification of Electrotechnical Equipment and Components (IECEE), Geneva, Switzerland. All rights reserved.

This publication may be reproduced in whole or in part for non-commercial purposes as long as the IECEE is acknowledged as copyright owner and source of the material. IECEE takes no responsibility for and will not assume liability for damages resulting from the reader's interpretation of the reproduced material due to its placement and context.

If this Test Report Form is used by non-IECEE members, the IECEE/IEC logo and the reference to the CB Scheme procedure shall be removed.

This report is not valid as a CB Test Report unless signed by an approved CB Testing Laboratory and appended to a CB Test Certificate issued by an NCB in accordance with IECEE 02.


Test item description..... : Fuse-links for the protection of semiconductor devices

Trade Mark..... : /

Manufacturer : Zhejiang Tengen Electrics Co., Ltd.

Model/Type reference..... : NHZ1-00, NHZ1-00S

Ratings..... : Un: DC80V,
In: 10A, 16A, 20A, 25A, 32A, 40A, 50A, 63A, 80A, 100A, 125A,
160A, 200A, 250A, 300A, 315A, 350A, 400A, 500A, 600A,
Rated breaking capacity I₁: 25kA,
Breaking range and utilization category: gS

Testing procedure and testing location:		
<input checked="" type="checkbox"/>	CB Testing Laboratory:	Suzhou Electrical Apparatus Science Research Institute Stock Co., Ltd.(EETI)
Testing location/ address		No.7 Yonghe Street, Binhe Road, New District, Suzhou, China
Tested by (name + signature).....:		Wang Wei
Approved by (name + signature)		Hu Delin
		
<input type="checkbox"/>	Testing procedure: TMP	
Testing location/ address		
Tested by (name + signature).....:		
Approved by (name + signature)		
<input type="checkbox"/>	Testing procedure: WMT	
Testing location/ address		
Tested by (name + signature).....:		
Witnessed by (name + signature)		
Approved by (name + signature)		
<input type="checkbox"/>	Testing procedure: SMT	
Testing location/ address		
Tested by (name + signature).....:		
Approved by (name + signature)		
Supervised by (name + signature)....:		